

**IMPEDANCE STUDIES ON THE SUB-MICRON GRAIN Yb-DOPED Ba(Ce,Zr)O<sub>3</sub> CERAMICS AT INTERMEDIATE TEMPERATURES**

N. Osman<sup>1,\*</sup>, I. A. Talib<sup>2</sup> and H. A. Hamid<sup>1</sup>

<sup>1</sup>*Faculty of Applied Sciences, Universiti Teknologi MARA, 02600 Arau, Perlis, Malaysia*

<sup>2</sup>*School of Applied Physics, Faculty of Science and Technology, Universiti Kebangsaan Malaysia, 43600 UKM Bangi, Selangor, Malaysia*

**ABSTRACT**

A ceramic of Ba(Ce<sub>0.6</sub>Zr<sub>0.4</sub>)<sub>0.95</sub>Yb<sub>0.05</sub>O<sub>2.975</sub> was prepared by the Pechini method. Morphology of the fractured surface of sintered pellet was observed using a scanning electron microscope. The sample formed clear and compact grains with submicron sizes. Impedance data were collected using a high frequency response analyzer under wet hydrogen in the temperature range from 200 to 800 °C. At  $T \leq 250^\circ\text{C}$ , the high frequency arc corresponding to grain response, the mid-frequency arc due to the grain boundary response, and low frequency arc attributed to the electrode/electrolyte interface were observed. Above 300°C, the grain resistance was obtained from the intercept of the grain boundary arc with the real axis at high frequency. It was also noticed that above 300°C, the Z-imaginary data at high frequencies changed its sign to positive values. All the responses were resolved by the fitting procedure using an equivalent circuit representing the brick-layer model. Arrhenius plot of proton conductivity and capacitances associated with the grain and grain boundary of Ba(Ce<sub>0.6</sub>Zr<sub>0.4</sub>)<sub>0.95</sub>Yb<sub>0.05</sub>O<sub>2.975</sub> are also presented.

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